

VAN RHEE ET AL. - 10/796,309  
Client/Matter: 081468-0308602

IN THE SPECIFICATION:

Please amend paragraph [0064] as follows:

In at least one embodiment, the processor 8 is arranged to filter out obvious errors such as measurement errors, local dirt on the substrate, or a focus spot itself. This is achieved by repeating all actions shown in figure 4 but with a so-called feedback height map (not shown) instead of with a measured height map 50. This feedback height map is fabricated by removing height information from the subtracted height map 66 of dies that overlap with the determined focus spots 68. ~~(In another embodiment, the feedback height map may be fabricated by removing, from the measured height map 50, height information of dies that overlap with the determined focus spots.)~~